INFORMATION DISCLOSURE	ATTY. DOCKET NO.		SERIAL N	O.	_
CITATION	4105-1	488	n/a	10/568,943	
	APPLICANT				
	n/a	APR 0 1 2009			
(Use several sheets if necessary)	FILING DATE	1	TC/A.U.		
	n/a	A. T. T. T.	n/a		

U.S. F	PAT	ENT	DOC	UMENTS
--------	-----	-----	-----	--------

DOCUMENT NUMBER	5.75				FILING DATE
DOCOMEN I NOMBEK		NA NAC	01 400	011001400	
	DATE	NAME	CLASS	SUBCLASS	IF APPROPRIATE
		Onoe et al.	19999999999999	000000000000000000000000000000000000000	
2004/0047245	03/2004	Onoe et al.	000000000000000000000000000000000000000	9990	
2004/0246879	12/2004	Onoe et al.	100000000000000000000000000000000000000	20000000	
5,864,445	01/1999	Bennin et al.	000000000000000000000000000000000000000	XXXXX0000000000	
6,418,091	07/2002	Hirokane et al.	090000055559990000	00000000000000000000000000000000000000	
7,020,064	03/2006	Kim et al.	000000000000000	9999999999999	
					
	-				
					\
					- ,
	5,864,445 6,418,091	2004/0047245 03/2004 2004/0246879 12/2004 5,864,445 01/1999 6,418,091 07/2002	2004/0047245 03/2004 Onoe et al. 2004/0246879 12/2004 Onoe et al. 5,864,445 01/1999 Bennin et al. 6,418,091 07/2002 Hirokane et al.	2004/0047245 03/2004 Onoe et al. 2004/0246879 12/2004 Onoe et al. 5,864,445 01/1999 Bennin et al. 6,418,091 07/2002 Hirokane et al.	2004/0047245 03/2004 Onoe et al. 2004/0246879 12/2004 Onoe et al. 5,864,445 01/1999 Bennin et al. 6,418,091 07/2002 Hirokane et al.

FOREIGN PATENT DOCUMENTS

					TRANSL	ATIOI
	DOCUMENT	DATE	COUNTRY	CLASS SUBCLASS	YES	NO
/PWH/	1 351 939	05/1974	GB	800000000000000000000000000000000000000		
1800	55 139643	10/1980	JP	500000000000000000000000000000000000000	ABSTRACT	
	59-22250	02/1984	JР	588880000000000000000000000000000000000	ABSTRACT	
	63-001175	01/1988	JР	\$0000000000000000000000000000000000000	ABSTRACT	
	06-267122	09/1994	JР	300000000000000000000000000000000000000	ABSTRACT	
8	08-212604	08/1996	ЛР	10000000000000000000000000000000000000		
0000	09-097457	04/1997	JР	000000000000000000000000000000000000000	ABSTRACT	
8	09-153235	06/1997	JP		ABSTRACT	
	09-222430	08/1997	ЛР	300000375750000000000000000000000000000	ABSTRACT	
0000	10-334525	12/1998	JР	G0000000000000000000000000000000000000	ABSTRACT	
	11-045467	02/1999	ЛР	100000000000000000000000000000000000000	ABSTRACT	
	11-176033	07/1999	JP	00000555500559000000000000055555559900	ABSTRACT	
	1 333 436	08/2003	EP	257555000000000000000000000000000000000		
000000	1 369 864	12/2003	EP	00000000000000000000000000000000000000		
1/	1 381 042	01/2004	EP	000000000000000000000000000000000000000		
V	1 398 779	03/2004	EP	>00000000000000000000000000000000000000		
PWH/	1 398 780	03/2004	EP	200000000000000000000000000000000000000	-	

*Examiner	/Paul Huber/	Date Considered	06/07/2009
C			

INFORMATION	DISCLOSURE
CITA	TION

ATTY. DOCKET NO.

SERIAL NO.

4105-74

10/568,943

APPLICANT

CHO et al.

FILING DATE (Use several sheets if necessary)

March 22, 2006

TC/A.U. 2627

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	FILING DATE
/PWH/	2003/0169672	09/2003	Onoe et al.	CLASS SUBCLASS IF APPROPRIATE
-/: VVII/	2004/0047245	03/2004	Onoe et al.	100000000000000000000000000000000000000
	2004/0246879	12/2004	Onoe et al.	800000000000000000000000000000000000000
	5,864,445	01/1999	Bennin et al.	000000000000000000000000000000000000000
V	6,418,091	07/2002 -	Hirokane et al.	999988000000000000000000000000000000000
/PWH/	7,020,064	03/2006	Kim et al.	100000000000000000000000000000000000000

Ì				

FOREIGN PATENT DOCUMENTS

					TRANSL	ATION
	DOCUMENT	DATE	COUNTRY	CLASS SUBCLASS	YES	NO
/PWH/	1 351 939	05/1974	GB	www.coccoccoccoccoccoccoccoccoccoccoccoccoc		
80	55 139643	10/1980	JP	200000000000000000000000000000000000000	ABSTRACT	
8000	59-22250	02/1984	JP	300000000000000000000000000000000000000	ABSTRACT	
	63-001175	01/1988	JP	200000000000000000000000000000000000000	ABSTRACT	
	06-267122	09/1994	JP	922225000000000000000000000000000000000	ABSTRACT	
	08-212604	08/1996	JP	10000000000000000000000000000000000000		
000	09-097457	04/1997	JP	000000000000000000000000000000000000000	ABSTRACT	
	09-153235	06/1997	JР	600000000000000000000000000000000000000	ABSTRACT	
8	09-222430	08/1997	JP	200000000000000000000000000000000000000	ABSTRACT	
	10-334525	12/1998	JP	(50000000000000000000000000000000000000	ABSTRACT	
	11-045467	02/1999	JP	1065535/29791000000 165531/99000000000553	ABSTRACT	
00000	11-176033	07/1999	JР	577757600000000000000000000000000000000	ABSTRACT	-
	1 333 436	08/2003	EP	215000000000000000000000000000000000000		
000000	1 369 864	12/2003	EP	000000000000000000000000000000000000000		
1/	1 381 042	01/2004	- EP	20xxxxxxxxxxxxxxxxxxxxxxxxxxxxxxxxxxxx		
V	1 398 779	03/2004	EP	10000000000000000000000000000000000000		
/PWH/	1 398 780	03/2004	EP	100000000000000000000000000000000000000		

*Examiner	/Paul Huber/	·	Date Considered	06/07/2009	

NFORMATION DISCLOSURE	ATTY. DOCKET NO.	SERIAL NO.	
CITATION	4105-74	10/568,943	
	APPLICANT		
	CHO et al.		
(Use several sheets if necessary)	FILING DATE	TC/A.U.	
	March 22, 2006	2627	

	March 22, 2006	2627	
	OTHER DOCUMENTS (including Author, Title,	Date, Pertinent pages, etc.)	
/PWH/	Society of Applied Physics Lecture Meeting (2001.9 Aichi Ins	titute of Technology) 12p-ZR-2. (Abstract)	_
***************************************	Kazuta et al, "Determination of crystal polarities of piezoelectr microscopy", Journal of European Ceramic Society 21 (2001)		
-	The Institution of Electrical Engineers, Stevenage, GB; 1 June formation in stoichiometric LiTaO/sub3/single crystal using Sc (Abstract)		
00000000000	Cho et al, "Scanning nonlinear dielectric microscopy with nand 21 (2001) 2131-2134.	ometer resolution", Journal of European Ceramic S	ociety
0000000000	Cho et al., "Nano domain engineering using scanning nonlinea 2001, pages 352-357.	r dielectric microscopy, October 29, 2001, IEE-NA	ANO
0000000000	Cho et al, "Tbit/inch ² ferroelectric data storage based on scann Letters, Vol. 81, No. 23, December 2, 2002, pages 4401-4403.	ing nonlinear dielectric microscopy", Applied Phys	sics
V	Odagawa et al, "Measuring ferroelectric polarization compone microscopy", Applied Physics Letters, vol. 80, No. 12, Mar. 25	•	lectric
PWH/	Matsuura et al, "Fundamental Study on Nano Domain Enginee Jpn. J. Appl. Phys. vol. 40 (2001) pp. 4354-4356, Part 1, No. 6		opy",

*Examiner /Paul Huber/ Date Considered 06/07/2009